

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/644,755	<b>Applicant(s)/Patent under Reexamination</b> LORTZ ET AL.
<b>Examiner</b> Anthony Weier	<b>Art Unit</b> 1794	

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner
426	422, 432		
	330.3		
	330.4		
106/483		1/14/2008	AW